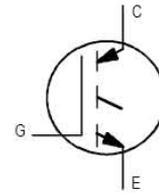


Features

- High short circuit rating optimized for motor control
- Low conduction losses
- High switching speed
- Tighter parameter distribution

$V_{CES}=1200\text{ V}$
 $V_{CE(on)\text{ typ. }}=3,2\text{ V}$
 @ $V_{GE}=15\text{ V}$, $I_C=30\text{ A}$



N-channel



TO-247AC

ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Units	Max
Collector-to-Emitter Voltage	V_{CES}	V	1200
Continuous Collector Current	$I_C @ T_C=25^\circ\text{C}$	A	30
Continuous Collector Current	$I_C @ T_C=100^\circ\text{C}$		15
Pulsed Collector Current ¹	I_{CM}		60
Clamped Inductive Load Current ²	I_{LM}		60
Short Circuit Withstand Time	tsc	μs	10
Maximum Power Dissipation	$P_D @ T_C=25^\circ\text{C}$	W	160
Maximum Power Dissipation	$P_D @ T_C=100^\circ\text{C}$		65
Gate-to-Emitter Voltage	V_{GE}	V	± 20
Operating Junction and Storage temperature Range	T_J T_{STG}	$^\circ\text{C}$	-55 to +150
Soldering Temperature, for 10 seconds		$^\circ\text{C}$	300

THERMAL RESISTANCE

Parameter	Symbol	Units	Min	Typ.	Max
Junction-to-Case	$R_{\theta JC}$	$^\circ\text{C/W}$	-	-	0,8
Case-to-Sink, Flat, Greased Surface	$R_{\theta CS}$		-	0,24	-
Junction-to-Ambient, typical socket mount	$R_{\theta JA}$		-	-	40

ELECTRICAL CHARACTERISTICS (T_J =25 °C)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Collector-to-Emitter Breakdown Voltage	V _{(BR)CES}	V	V _{GE} = 0V, I _C = 250μA	1200	-	-
Breakdown Voltage Temp.Coefficient	ΔV _{(BR)CES} /ΔT _J	V/°C	V _{GE} = 0V, I _C = 1 mA	-	0,4	-
Collector-to-Emitter Saturation Voltage	V _{CE(ON)}	V	V _{GE} = 15V, I _C = 15A	-	2,7	3,3
			V _{GE} = 15V, I _C = 30A	-	3,2	-
			V _{GE} = 15V, I _C = 15A T _J =150°C	-	2,6	-
Gate Threshold Voltage	V _{GE(th)}	V	V _{GE} =V _{CE} , I _C =250 μA	3,0	-	6,0
Threshold Voltage Temp.Coefficient	ΔV _{(GE)th} /ΔT _J	mV/°C	V _{GE} =V _{CE} , I _C =2mA	-	-3,5	-
Forward Transconductance	g _(fe)	S	V _{CE} = 100V, I _C = 15 A	8,0	14	-
Zero Gate Voltage Collector Current	I _{CES}	μA	V _{CE} = 1200V, V _{GE} =0V	-	-	250
			V _{CE} = 10V, V _{GE} =0V	-	-	2,0
			V _{CE} = 1200V, V _{GE} =0V T _J =150°C	-	-	3000
Gate-to-Emitter Leakage Current	I _{GES}	nA	V _{GS} = ±20V			±100

SWITCHING CHARACTERISTICS (T_J =25 °C)

Parameter	Symbol	Units	Test Conditions	Min	Typ.	Max
Total Gate Charge (turn on)	Q _g	nC	V _{GE} = 15V, V _{CC} = 400V, I _C =15A	-	98	140
Gate-to-Emitter Charge (turn on)	Q _{ge}			-	18	22
Gate-to-Collector Charge (turn on)	Q _{gc}			-	45	55
Turn-On Delay Time	t _{d(on)}	ns	V _{CC} =960V, I _C =15A V _{GE} = 15V R _G =24 Ω	-	31	-
Rise Time	t _r			-	23	-
Turn-Off Delay Time	t _{d(off)}			-	230	300
Fall Time	t _f			-	180	238
Turn-On Switching Loss	E _{on}	mJ	Energy losses include «tail»	-	1,0	-
Turn-Off Switching Loss	E _{off}			-	1,8	-
Total Switching Loss	E _{ts}			-	2,5	2,9
Short Circuit Withstand Time	t _{sc}	μs	V _{CC} =720V, T _J =125°C V _{GE} =15V R _G =5,0Ω	10	-	-
Turn-On Delay Time	t _{d(on)}	ns	T _J =150°C V _{CC} =960V, I _C =15A V _{GE} = 15V R _G =24 Ω Energy losses include «tail»	-	32	-
Rise Time	t _r			-	27	-
Turn-Off Delay Time	t _{d(off)}			-	970	-
Fall Time	t _f			-	360	-
Total Switching Loss	E _{ts}	mJ		-	5,0	-
Input Capacitance	C _{ISS}	pF	V _{GE} = 0V, V _{CC} = 30V, f = 1.0MHz	-	1800	-
Output Capacitance	C _{OSS}			-	80	-
Reverse Transfer Capacitance	C _{RSS}			-	40	-

Notes:

¹ Repetitive rating; V_{GE} =20V, pulse width limited by max junction temperature.

² V_{CC}=80%(V_{CES}), L= 10 μH, V_{GE} = 20V, R_G=10 Ω.

³ Pulse width ≤80 μs, duty factor ≤0,1%.

⁴ Pulse width 5,0μs single short.

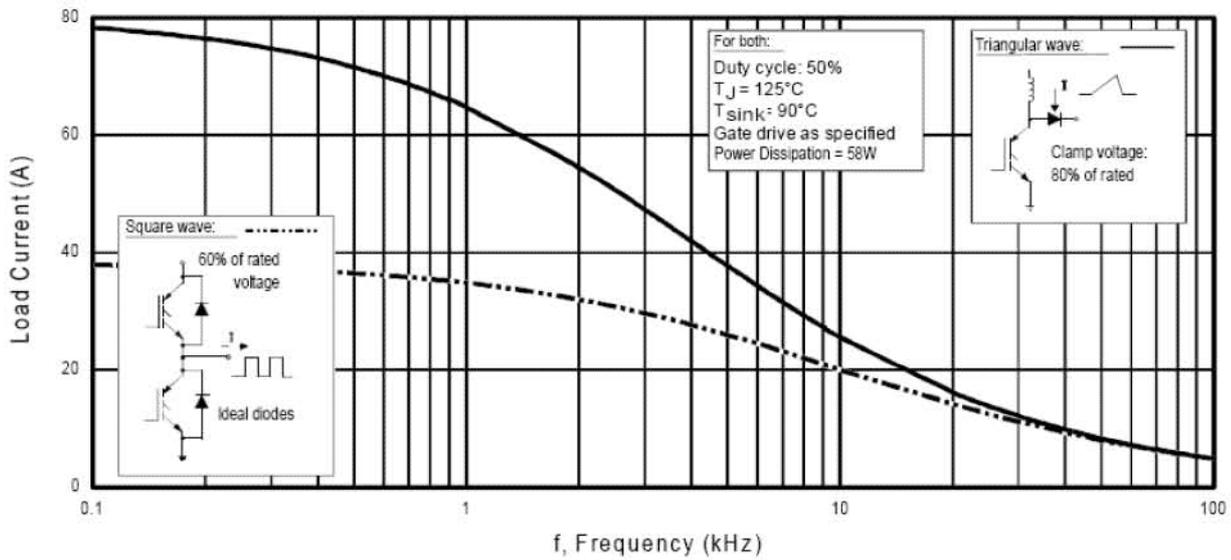


Fig.1 – Typical Load Current vs. Frequency
(For square wave, $I = I_{RMS}$ of fundamental; for triangular wave, $I = I_{PK}$)

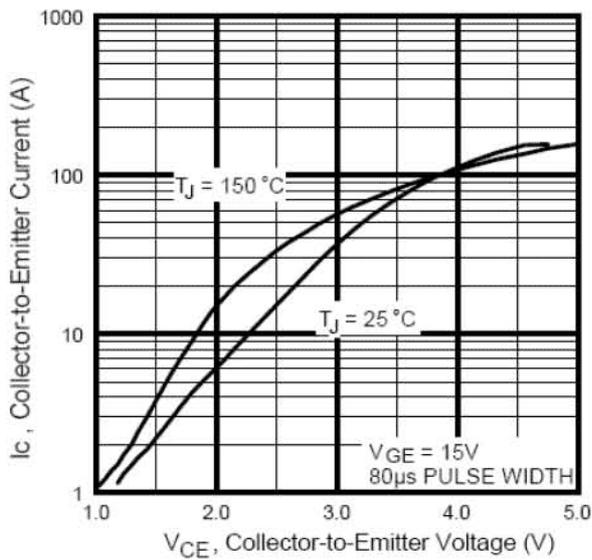


Fig.2 – Typical Output Characteristics

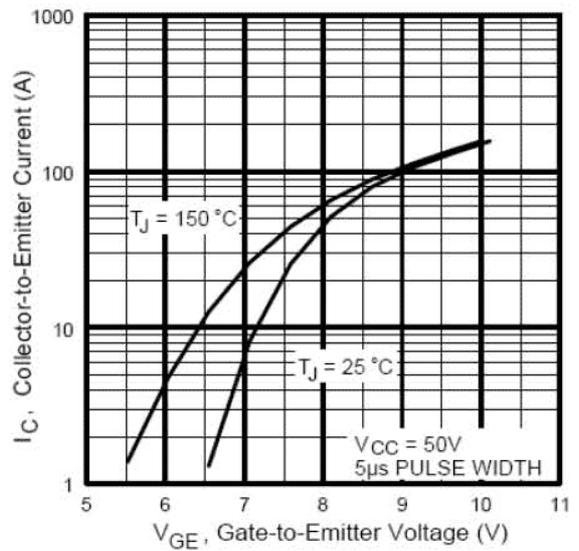


Fig.3 – Typical Transfer Characteristics

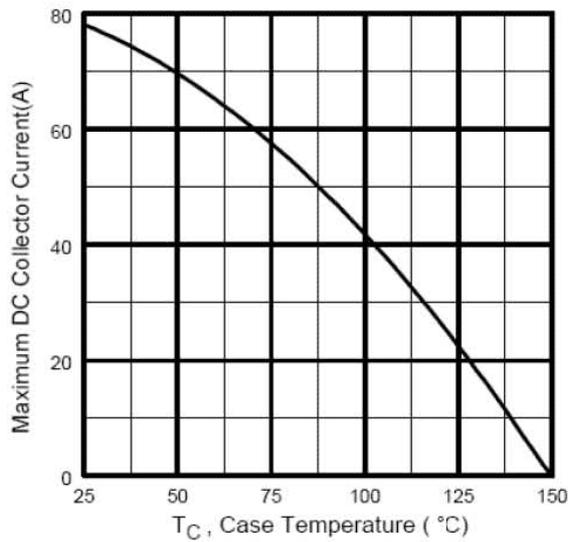


Fig.4 – Maximum Collector Current vs. Case Temperature

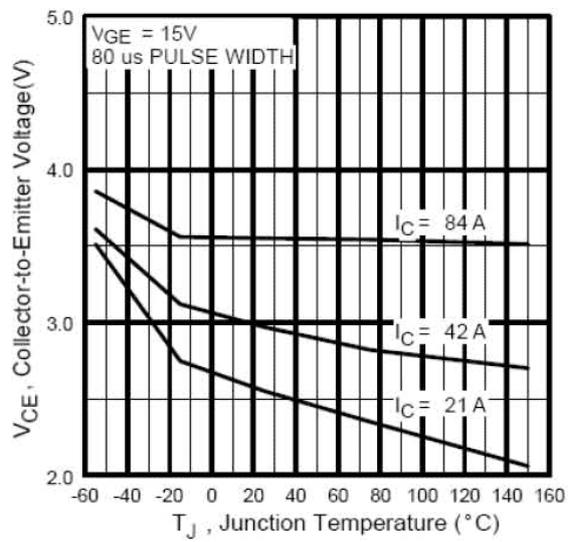


Fig.5 – Collector-to-Emitter Voltage VS. Junction Temperature

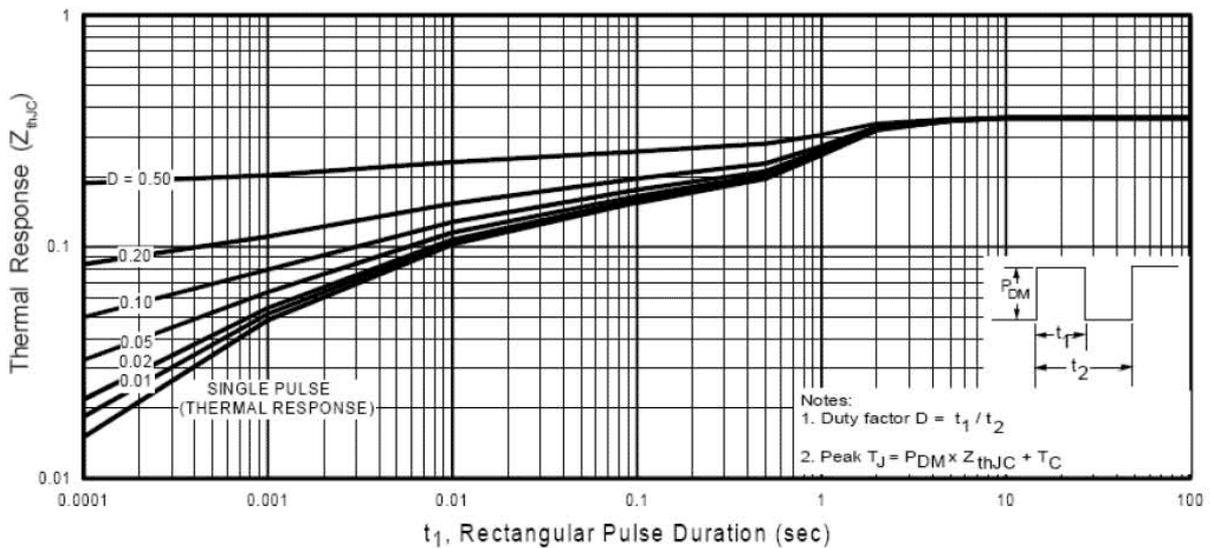


Fig.6 – Maximum Effective Transient Thermal Impedance, Junction-to-Case

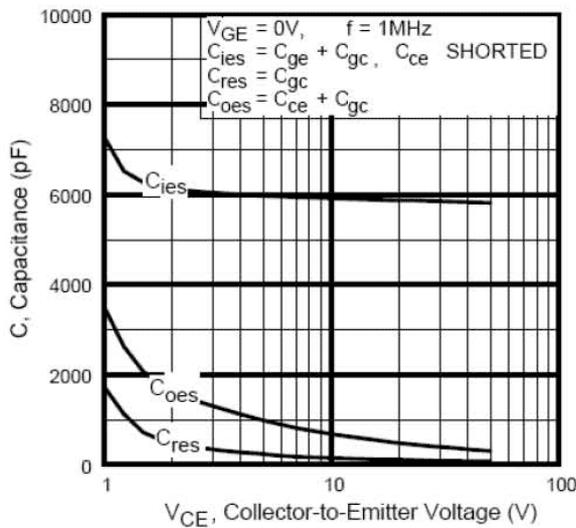


Fig.7 – Typical Capacitance vs. Collector-to-Emitter Voltage

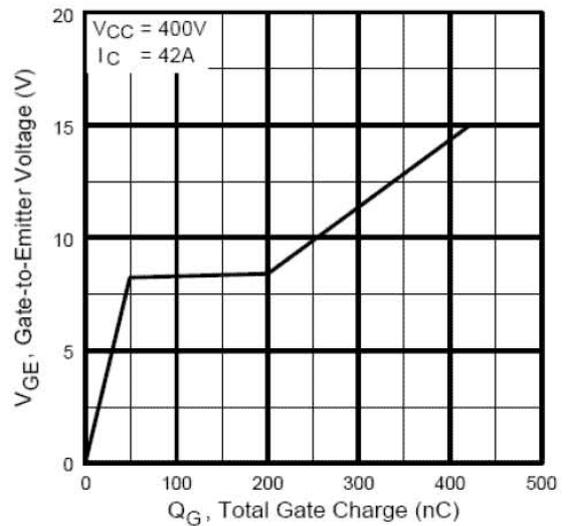


Fig.8 – Typical Gate Charge vs. Gate-to-Emitter Voltage

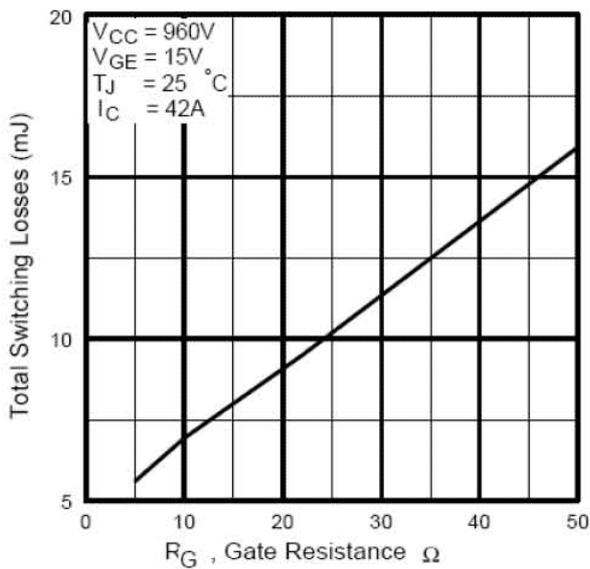


Fig.9 – Typical Switching Losses vs. Gate Resistance

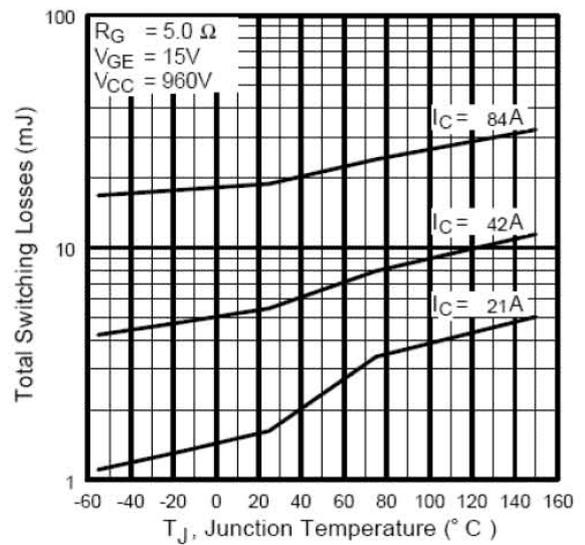


Fig.10 – Typical Switching Losses vs. Junction Temperature

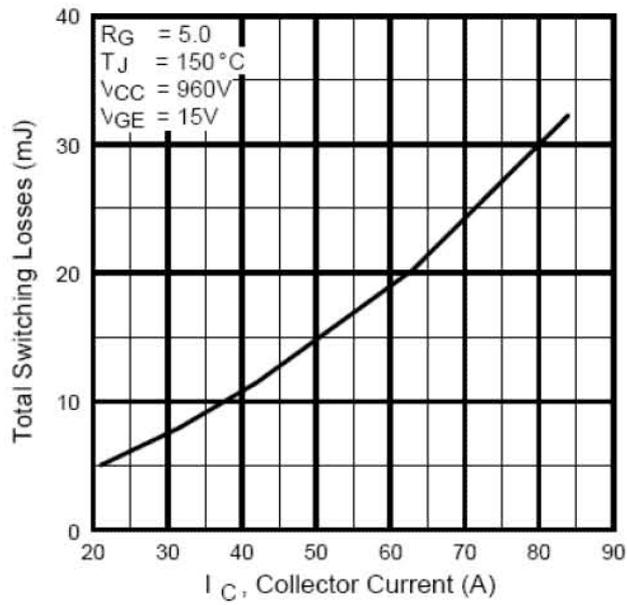


Fig. 11 – Typical Switching Losses vs. Collector-to-Emitter Current

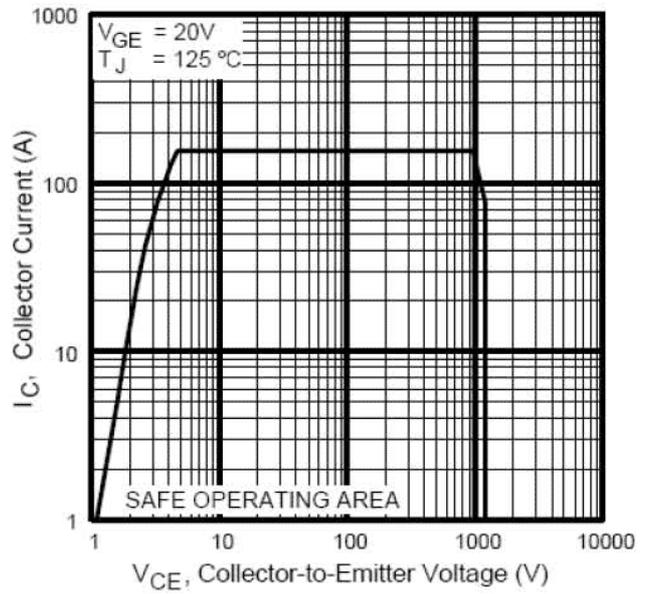
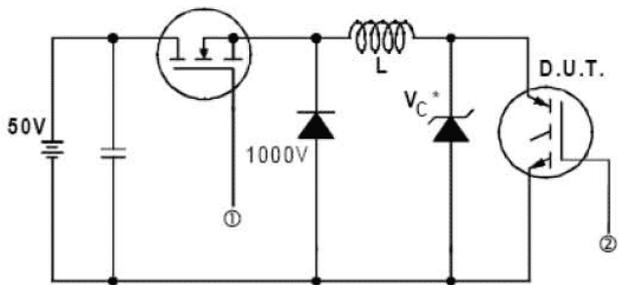


Fig.12-Turn-Off SOA



* Driver same type as D.U.T.; $V_c = 80\%$ of $V_{ce(max)}$
* Note: Due to the 50V power supply, pulse width and inductor will increase to obtain rated I_d .

Fig. 13a – Clamped Inductive Load Test Circuit

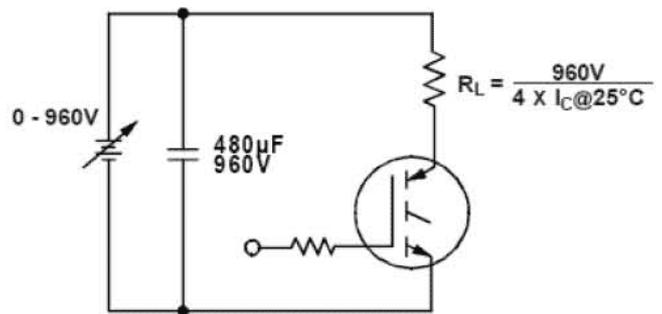


Fig.13b – Pulsed Collector Current Test Circuit

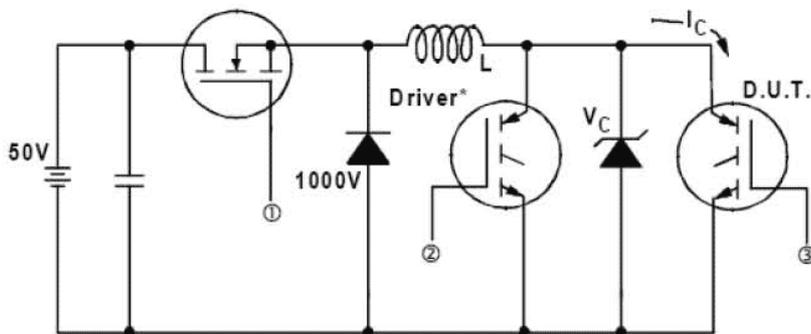


Fig. 14a - Switching Loss Test Circuit

* Driver same type as D.U.T., $V_C = 960V$

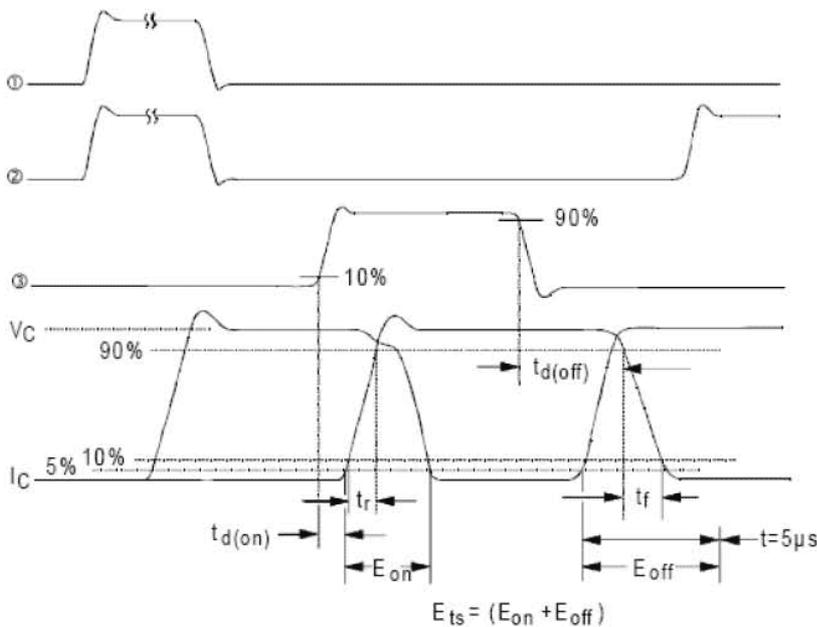


Fig. 14b - Switching Loss Waveforms